

SME6006V GaN TRANSISTOR

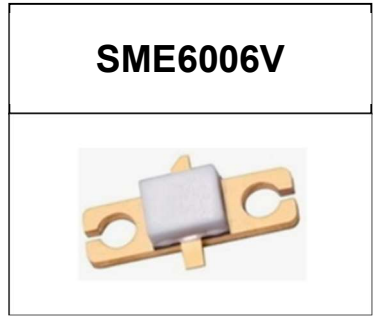
Document Number: SME6006V
Product Datasheet V1.0

Gallium Nitride 50V 60W, RF Power Transistor

Description

The SME6006V is a 60W single ended, unmatched GaN HEMT, designed for multiple applications with frequencies up to 4.2GHz.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.



• Typical performance (on Innogration narrow band production fixture with device soldered)

$V_{DD}=50V$ $I_{DQ}=15mA$, Pulse CW, pulse width: 20us, duty cycle: 10%

| Freq (MHz) | P1dB (dBm) | P1dB (W) | P1dB Eff (%) | P1dB Gain (dB) | P3dB (dBm) | P3dB (W) | P3dB Eff (%) |
|------------|------------|----------|--------------|----------------|------------|----------|--------------|
| 3400 | 47.72 | 59.2 | 62.2 | 14.28 | 48.63 | 73.0 | 63.0 |
| 3500 | 47.51 | 56.3 | 62.3 | 14.81 | 48.46 | 70.1 | 63.3 |
| 3600 | 46.39 | 43.5 | 59.2 | 14.77 | 47.72 | 60.2 | 62.8 |

Applications and Features

- Suitable for wireless communication infrastructure, wideband amplifier, EMC testing, ISM etc.
- High Efficiency and Linear Gain Operations
- Thermally Enhanced Industry Standard Package
- High Reliability Metallization Process
- Excellent thermal Stability and Excellent Ruggedness
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC

Important Note: Proper Biasing Sequence for GaN HEMT Transistors

Turning the device ON

1. Set VGS to the pinch-off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage (50V)
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V
3. Reduce VDS down to 0 V
4. Turn off VGS

Table 1. Maximum Ratings

| Rating | Symbol | Value | Unit |
|--------------------------------|-----------|-------------|------|
| Drain--Source Voltage | V_{DSS} | +200 | Vdc |
| Gate--Source Voltage | V_{GS} | -8 to 0 | Vdc |
| Operating Voltage | V_{DD} | 0 to 55 | Vdc |
| Maximum forward gate current | I_{gf} | 8 | mA |
| Storage Temperature Range | T_{stg} | -65 to +150 | C |
| Case Operating Temperature | T_c | -55 to +150 | C |
| Operating Junction Temperature | T_j | +225 | C |

Table 2. Thermal Characteristics

| Characteristic | Symbol | Value | Unit |
|--|-----------------|-------|------|
| Thermal Resistance, Junction to Case $T_c=85^{\circ}C$, $T_j=200^{\circ}C$, DC Power Dissipation, FEA | $R_{\theta JC}$ | 4.1 | C/W |

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Table 3. Electrical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

DC Characteristics

| Characteristic | Conditions | Symbol | Min | Typ | Max | Unit |
|--------------------------------|---|--------------|-----|------|-----|------|
| Drain-Source Breakdown Voltage | $V_{GS}=-8\text{V}; I_{DS}=8\text{mA}$ | V_{DSS} | | 200 | | V |
| Gate Threshold Voltage | $V_{DS} = 50\text{V}, I_D = 8\text{mA}$ | $V_{GS(th)}$ | | -3.4 | | V |
| Gate Quiescent Voltage | $V_{DS} = 50\text{V}, I_{DS}=100\text{mA}$, Measured in Functional Test | $V_{GS(Q)}$ | | -3 | | V |

Functional Tests (In Innogration broadband Test Fixture, 50 ohm system) : $V_{DD} = 50\text{Vdc}$, $I_{DQ} = 15\text{mA}$, $f = 3500\text{MHz}$, Pulse CW

| Characteristic | Symbol | Min | Typ | Max | Unit |
|---|--------|-----|------|-----|--------|
| Power Gain @ P3dB | Gp | | 12 | | dB |
| Drain Efficiency@P3dB _t | Eff | 60 | | | % |
| 3dB Compressed point | P3dB | 60 | | | W |
| Input Return Loss | IRL | | -7 | | dB |
| Mismatch stress at all phases(No device damage) | VSWR | | 10:1 | | Ψ |

Reference Circuit of Test Fixture Assembly Diagram

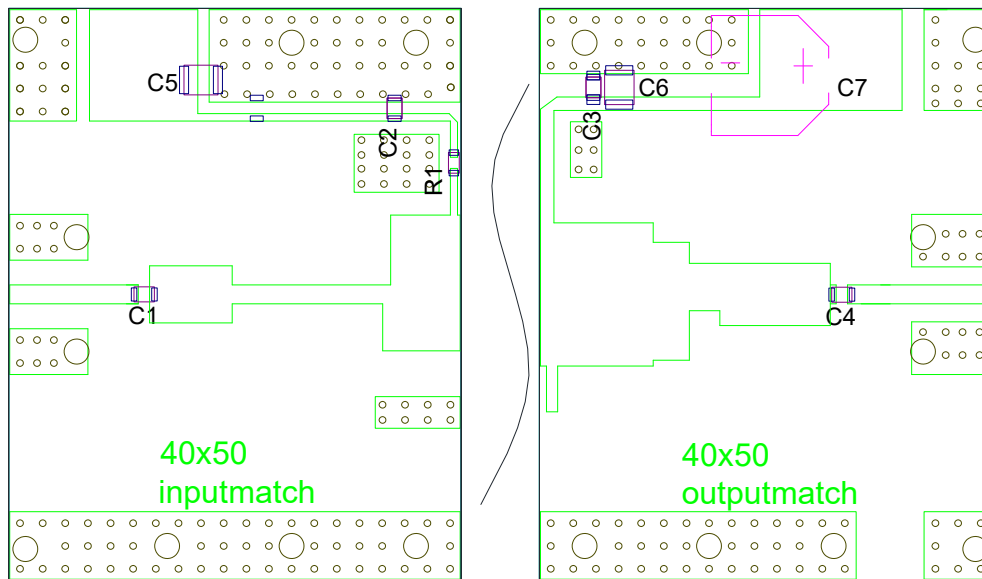


Figure 1. Test Circuit Component Layout (3400-3600MHz)

Table 4. Test Circuit Component Designations and Values

| Designator | Footprint | Comment | Quantity |
|----------------|-----------|-----------|----------|
| C1, C2, C3, C4 | 0805 | 6.8 pF | 4 |
| C5, C6 | 1210 | 10uF/100V | 2 |
| C7 | | 100uF/63V | 1 |
| R1 | 0603 | 10R | 1 |

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Figure 2. Power Gain and Efficiency Vs frequency

Vgs = -3.09V, VDS= 50V, IDQ = 100mA, Pulsed CW, 20uS width, 10% dule cycle.

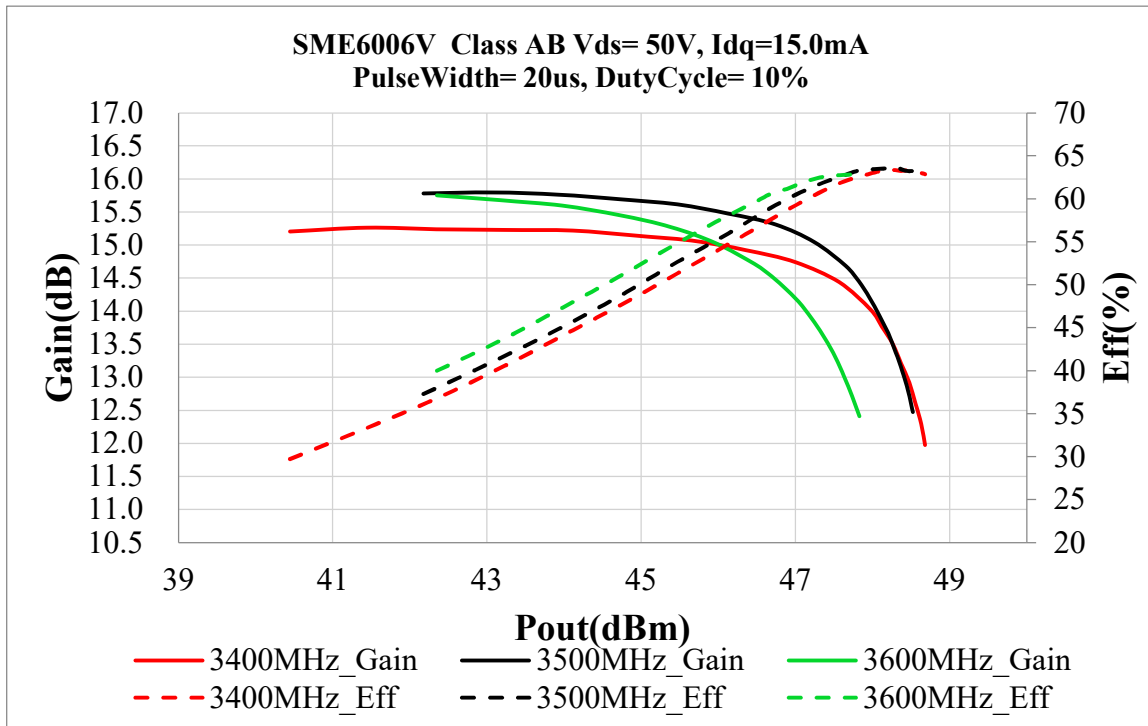
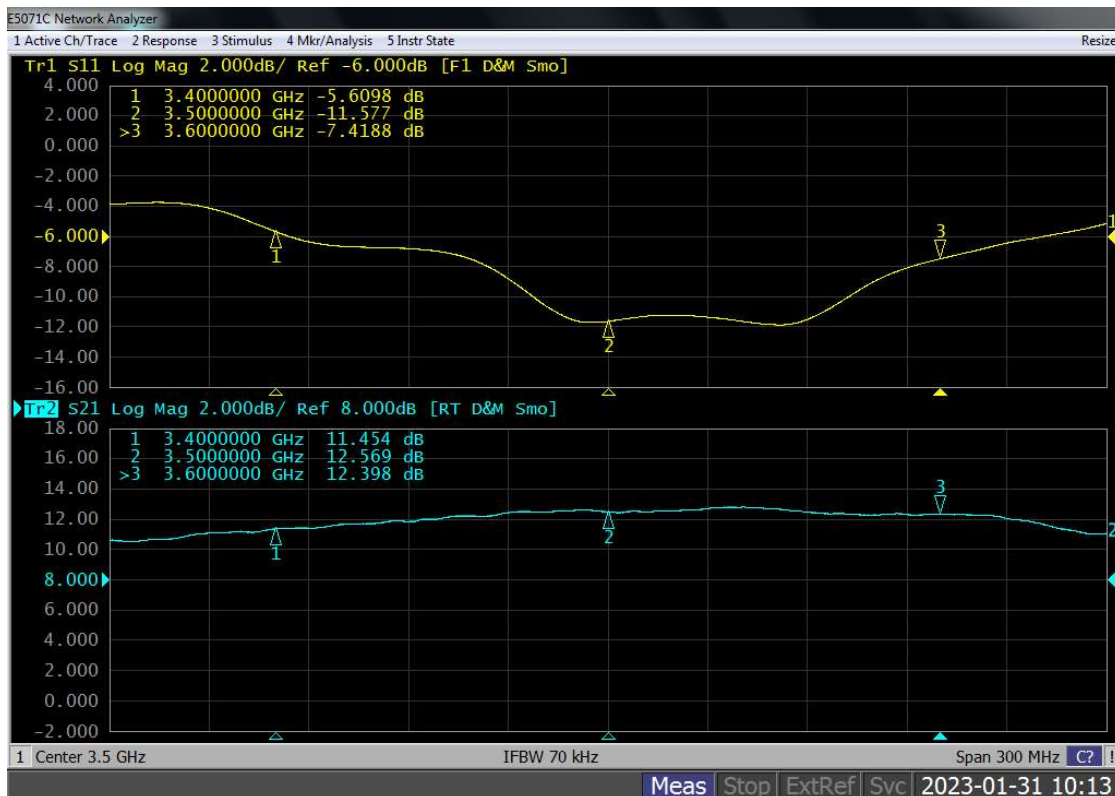


Figure 3. Network Analyzer result S11 and S21 Vgs = -3.09V, VDS= 50V, IDQ = 100mA



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Package Outline

Flanged ceramic package; 2 leads

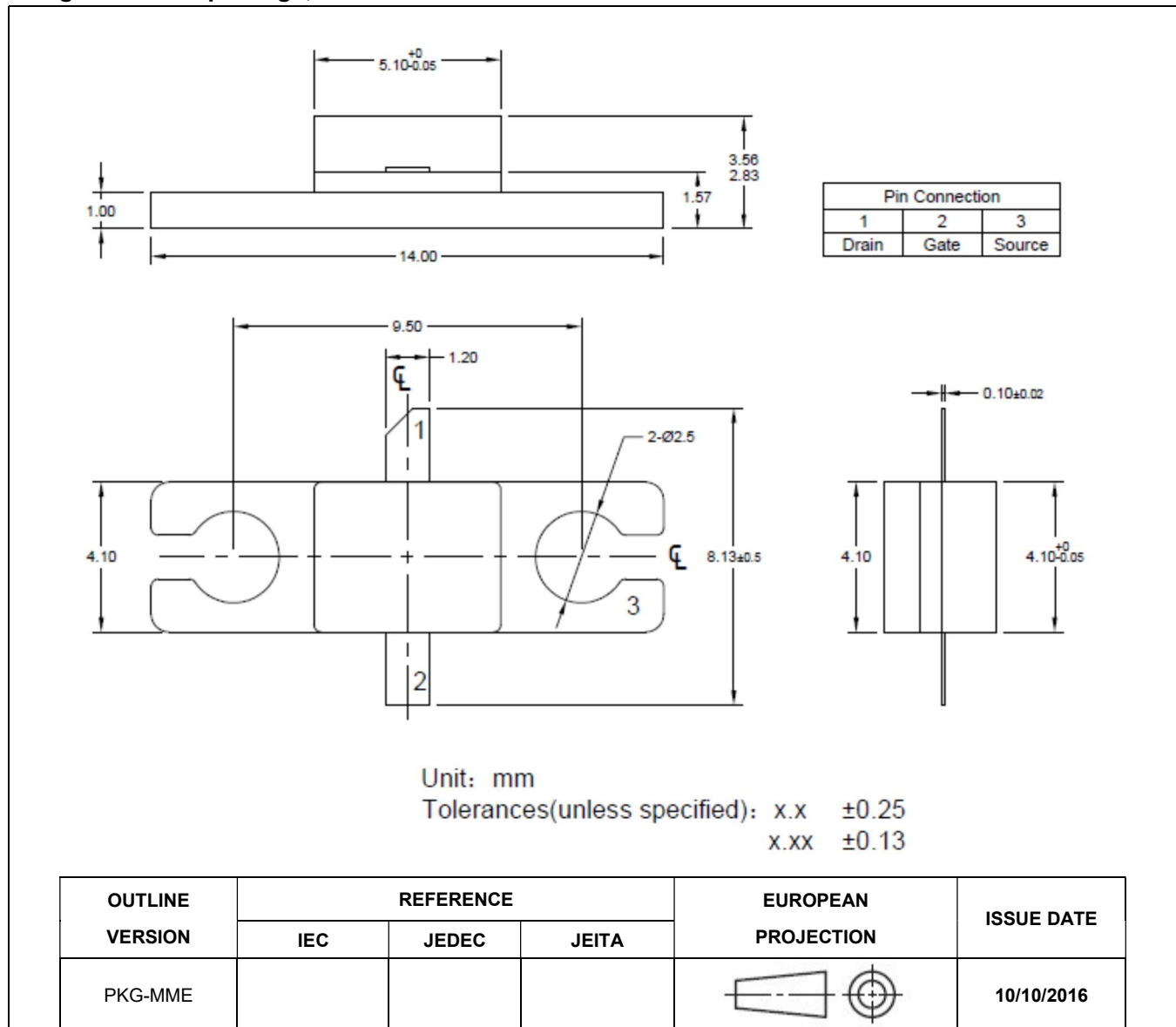


Figure 1. Package Outline PKG-MME

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Revision history

Table 4. Document revision history

| Date | Revision | Datasheet Status |
|-----------|----------|-------------------|
| 2023/1/31 | V1.0 | Product Datasheet |
| | | |

Application data based on LSM-23-03

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